

TOSHIBA CMOS Linear Integrated Circuit Silicon Monolithic

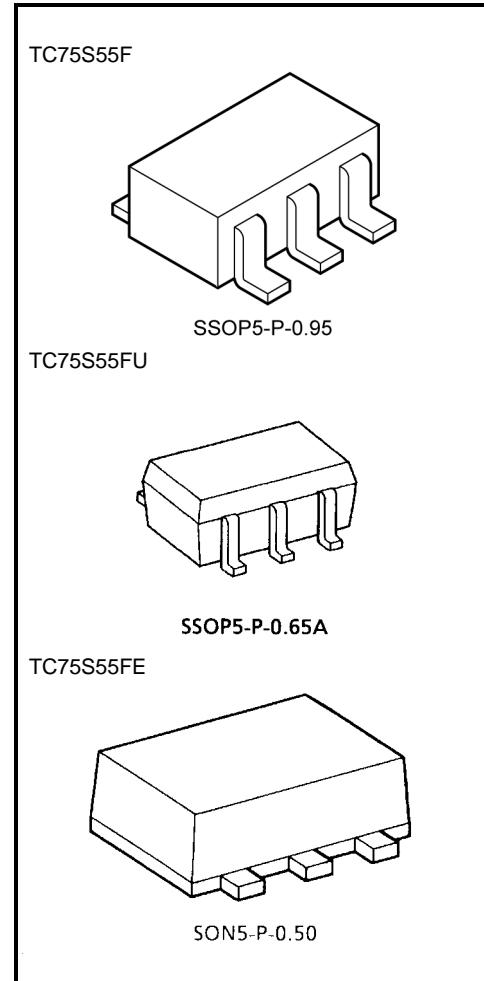
# TC75S55F, TC75S55FU, TC75S55FE

## Single Operational Amplifier

The TC75S55F/TC75S55FU/TC75S55FE is a CMOS single-operation amplifier which incorporates a phase compensation circuit. It is designed for use with a low-voltage, low-current power supply; this differentiates this device from conventional general-purpose bipolar op-amps.

### Features

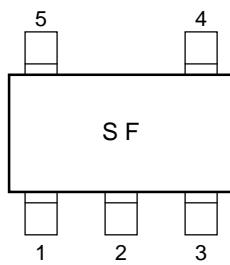
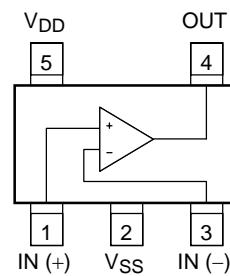
- Low-voltage operation :  $V_{DD} = \pm 0.9 \sim 3.5$  V or  $1.8 \sim 7$  V
- Low-current power supply :  $IDD (V_{DD} = 3$  V) =  $10 \mu A$  (typ.)
- Built-in phase-compensated op-amp, obviating the need for any external device
- Ultra-compact package



Weight  
 SSOP5-P-0.95 : 0.014 g (typ.)  
 SSOP5-P-0.65A : 0.006 g (typ.)  
 SON5-P-0.50 : 0.003 g (typ.)

### Maximum Ratings ( $T_a = 25^\circ C$ )

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{DD}, V_{SS}$	7	V
Differential input voltage	$DV_{IN}$	$\pm 7$	V
Input voltage	$V_{IN}$	$V_{DD} \sim V_{SS}$	V
Power dissipation	TC75S55F/FU	200	mW
	TC75S55FE	100	
Operating temperature	$T_{opr}$	-40~85	°C
Storage temperature	$T_{stg}$	-55~125	°C

**Marking (top view)****Pin Connection (top view)****Electrical Characteristics****DC Characteristics ( $V_{DD} = 3.0 \text{ V}$ ,  $V_{SS} = \text{GND}$ ,  $T_a = 25^\circ\text{C}$ )**

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Input offset voltage	$V_{IO}$	1	$R_S = 10 \text{ k}\Omega$	—	2	10	mV
Input offset current	$I_{IO}$	—	—	—	1	—	pA
Input bias current	$I_I$	—	—	—	1	—	pA
Common mode input voltage	$CMV_{IN}$	2	—	0.0	—	2.1	V
Voltage gain (open loop)	$G_V$	—	—	60	70	—	dB
Maximum output voltage	$V_{OH}$	3	$R_L \geq 1 \text{ M}\Omega$	2.9	—	—	V
	$V_{OL}$	4	$R_L \geq 1 \text{ M}\Omega$	—	—	0.1	
Common mode input signal Rejection Ratio	$CMRR$	2	$V_{IN} = 0.0\sim2.1 \text{ V}$	60	70	—	dB
Supply voltage rejection ratio	$SVRR$	1	$V_{DD} = 1.8\sim7.0 \text{ V}$	60	70	—	dB
Supply current	$I_{DD}$	5	—	—	10	20	$\mu\text{A}$
Source current	$I_{source}$	6	—	10	20	—	$\mu\text{A}$
Sink current	$I_{sink}$	7	—	100	450	—	$\mu\text{A}$

**DC Characteristics ( $V_{DD} = 1.8 \text{ V}$ ,  $V_{SS} = \text{GND}$ ,  $T_a = 25^\circ\text{C}$ )**

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Input offset voltage	$V_{IO}$	1	$R_S = 100 \text{ k}\Omega$	—	2	10	mV
Input offset current	$I_{IO}$	—	—	—	1	—	pA
Input bias current	$I_I$	—	—	—	1	—	pA
Common mode input voltage	$CMV_{IN}$	2	—	0.0	—	0.9	V
Voltage gain (open loop)	$G_V$	—	—	60	70	—	dB
Maximum output voltage	$V_{OH}$	3	$R_L \geq 1 \text{ M}\Omega$	1.7	—	—	V
	$V_{OL}$	4	$R_L \geq 1 \text{ M}\Omega$	—	—	0.1	
Supply current	$I_{DD}$	5	—	—	8	16	$\mu\text{A}$
Source current	$I_{source}$	6	—	8	16	—	$\mu\text{A}$
Sink current	$I_{sink}$	7	—	100	400	—	$\mu\text{A}$

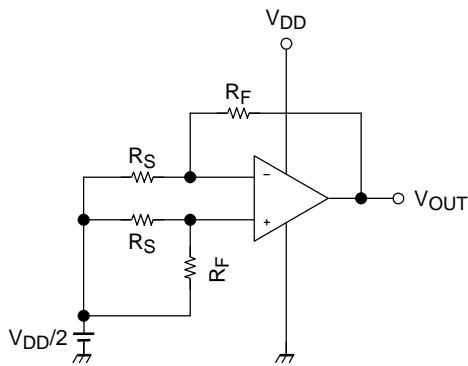
AC Characteristics ( $V_{DD} = 3.0$  V,  $V_{SS} = GND$ ,  $T_a = 25^\circ C$ )

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Slew rate	SR	—	—	—	0.08	—	V/ $\mu$ s
Unity gain cross frequency	f <sub>T</sub>	—	—	—	160	—	kHz

AC Characteristics ( $V_{DD} = 1.8$  V,  $V_{SS} = GND$ ,  $T_a = 25^\circ C$ )

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Slew rate	SR	—	—	—	0.06	—	V/ $\mu$ s
Unity gain cross frequency	f <sub>T</sub>	—	—	—	140	—	kHz

## Test Circuit

1. SVRR,  $V_{IO}$ 

- SVRR  
For each of the two  $V_{DD}$  values, measure the  $V_{OUT}$  value, as indicated below, and calculate the value of SVRR using the equation shown.

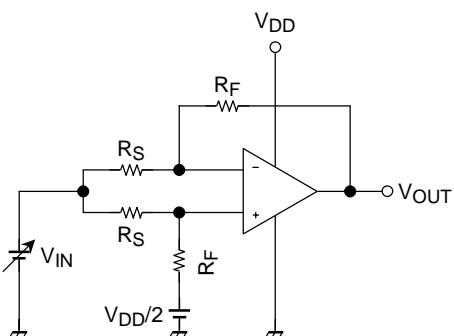
When  $V_{DD} = 1.8$  V,  $V_{DD} = V_{DD1}$  and  $V_{OUT} = V_{OUT1}$

When  $V_{DD} = 7.0$  V,  $V_{DD} = V_{DD2}$  and  $V_{OUT} = V_{OUT2}$

$$SVRR = 20 \log \left( \left| \frac{V_{OUT1} - V_{OUT2}}{V_{DD1} - V_{DD2}} \right| \times \frac{R_S}{R_F + R_S} \right)$$

- $V_{IO}$   
Measure the value of  $V_{OUT}$  and calculate the value of  $V_{IO}$  using the following equation.

$$V_{IO} = \left( V_{OUT} - \frac{V_{DD}}{2} \right) \times \frac{R_S}{R_F + R_S}$$

2. CMRR,  $CMV_{IN}$ 

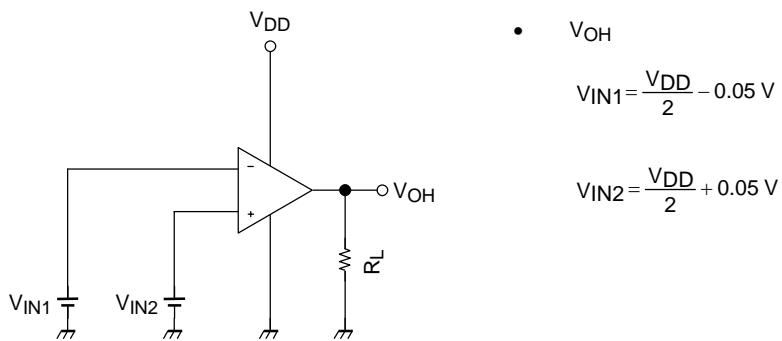
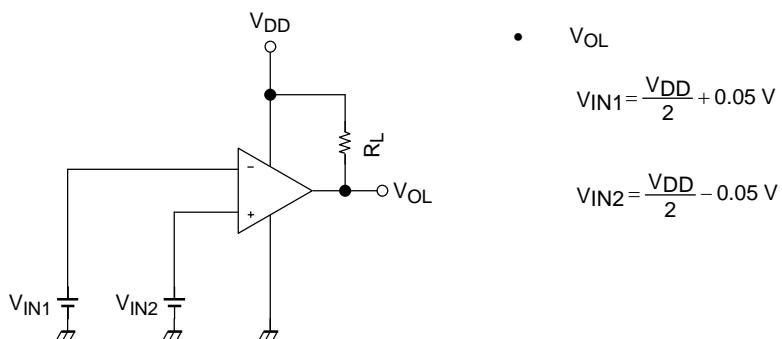
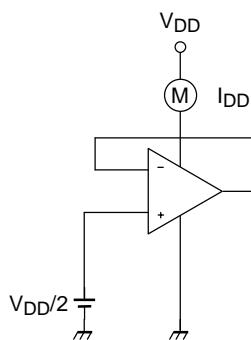
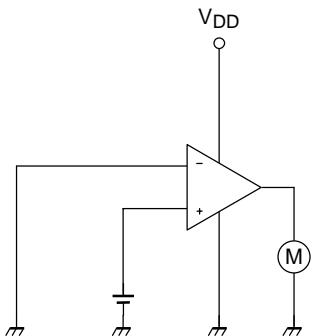
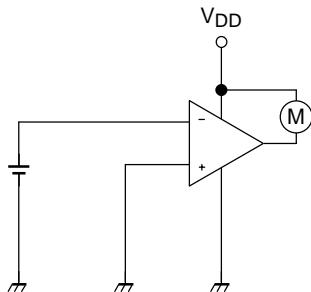
- CMRR  
Measure the  $V_{OUT}$  value, as indicated below, and calculate the value of the CMRR using the equation shown.

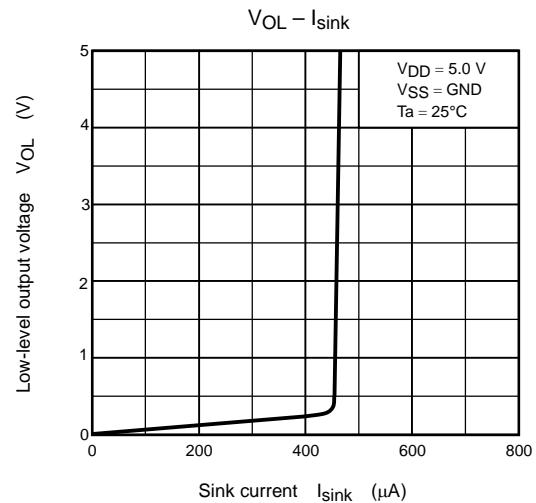
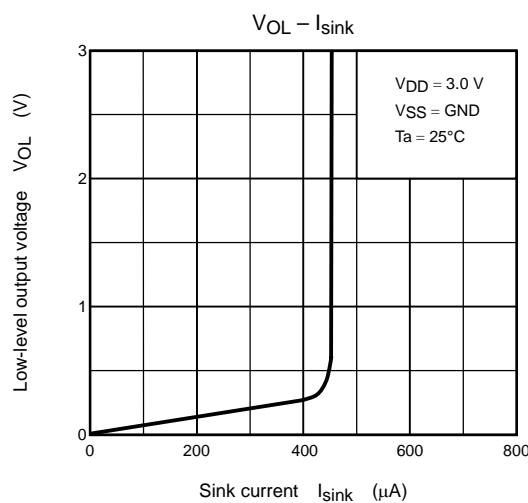
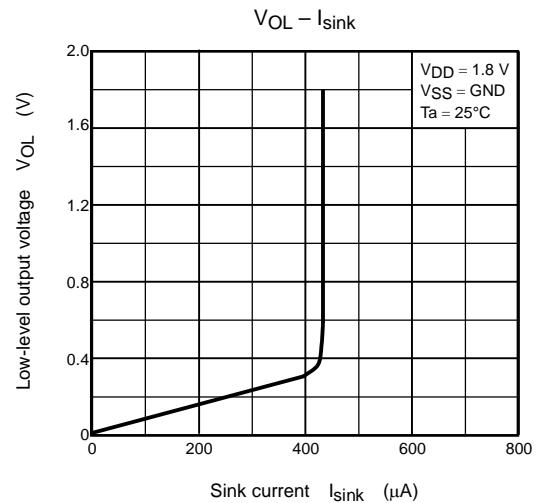
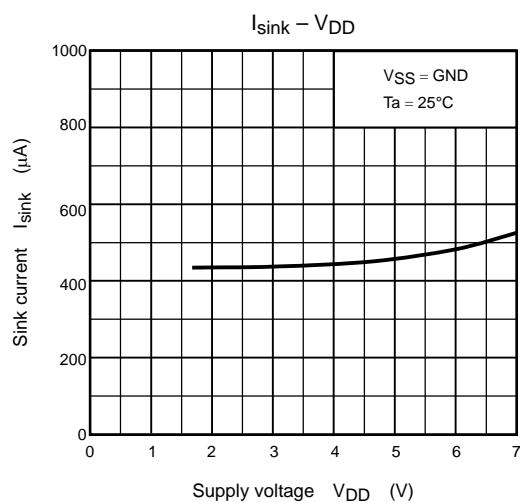
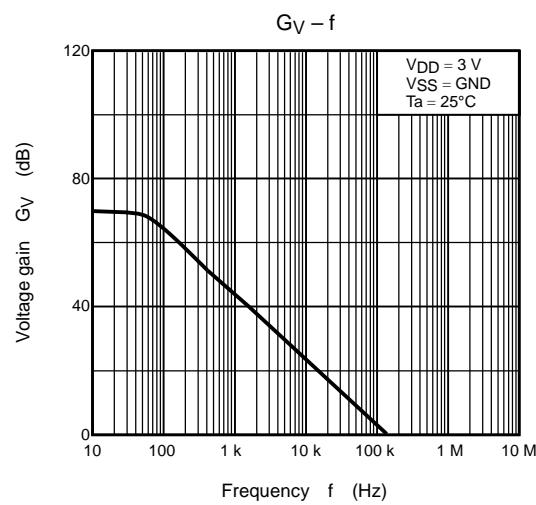
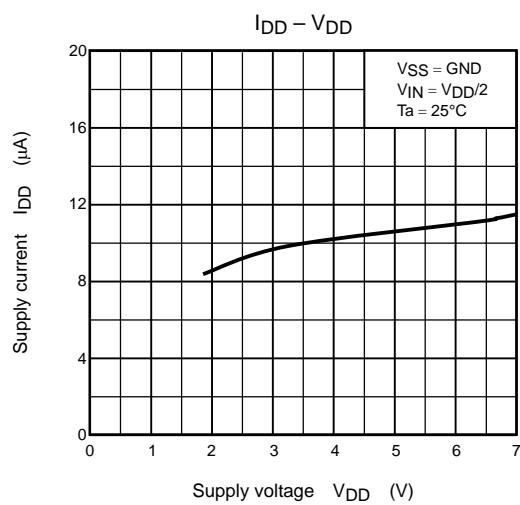
When  $V_{IN} = 0.0$  V,  $V_{IN} = V_{IN1}$  and  $V_{OUT} = V_{OUT1}$

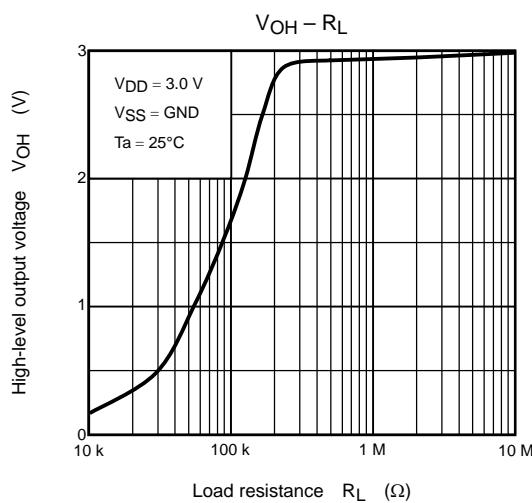
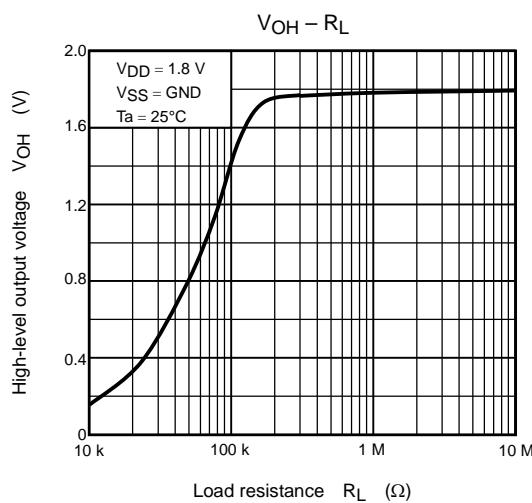
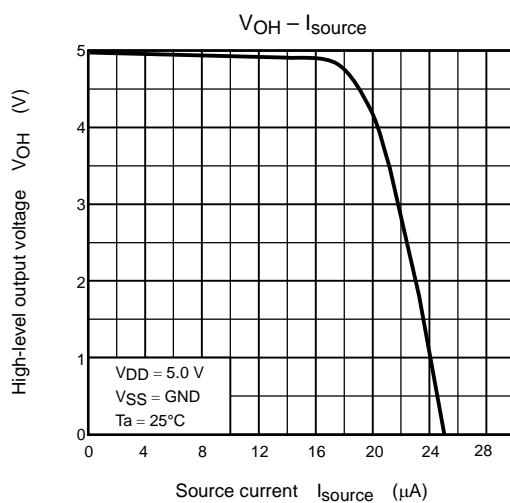
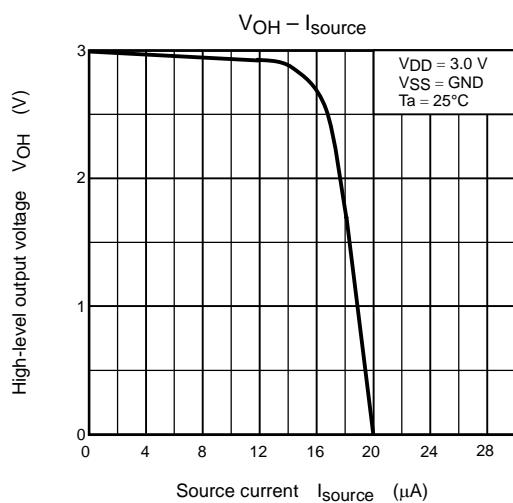
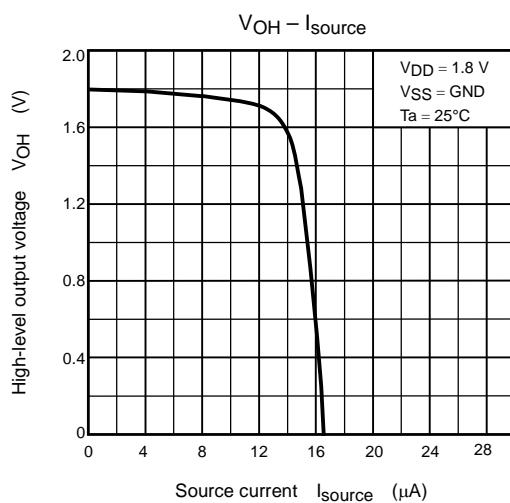
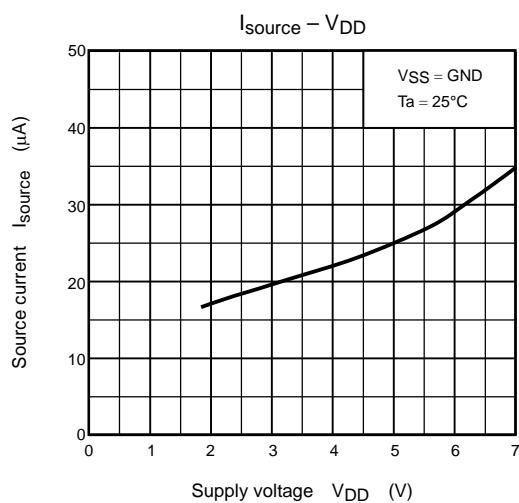
When  $V_{IN} = 2.1$  V,  $V_{IN} = V_{IN2}$  and  $V_{OUT} = V_{OUT2}$

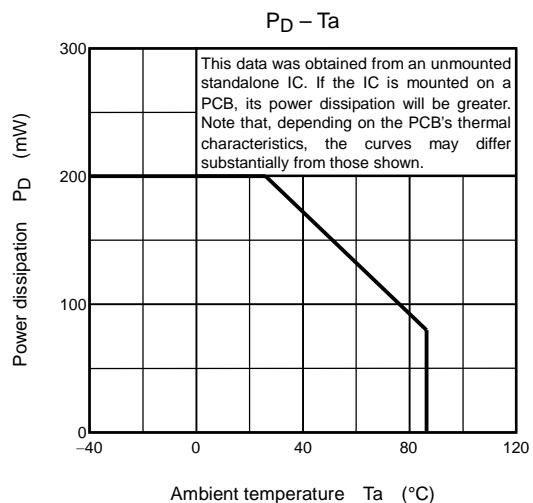
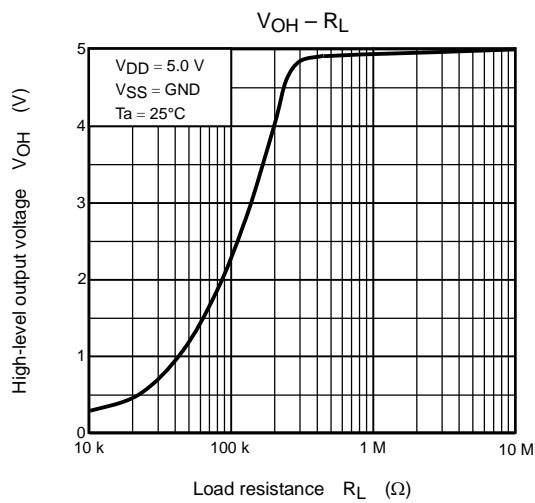
$$CMRR = 20 \log \left( \left| \frac{V_{OUT1} - V_{OUT2}}{V_{IN1} - V_{IN2}} \right| \times \frac{R_S}{R_F + R_S} \right)$$

- $CMV_{IN}$   
Input range within which the CMRR specification guarantees  $V_{OUT}$  value (as varied by the  $V_{IN}$  value).

3.  $V_{OH}$ 4.  $V_{OL}$ 5.  $I_{DD}$ 6.  $I_{source}$ 7.  $I_{sink}$ 



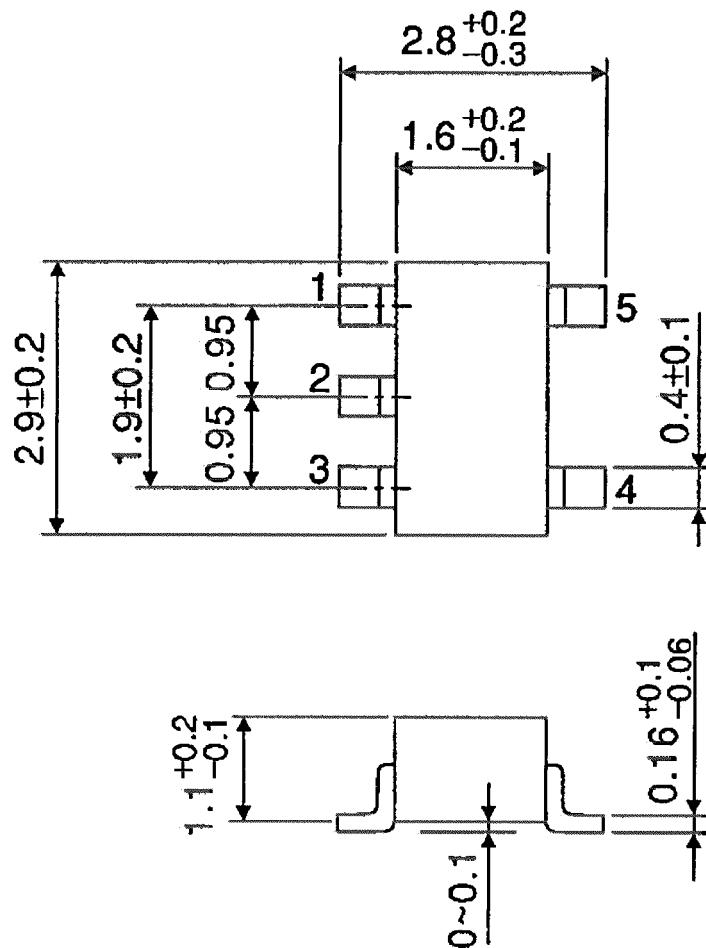




**Package Dimensions**

SSOP5-P-0.95

Unit : mm

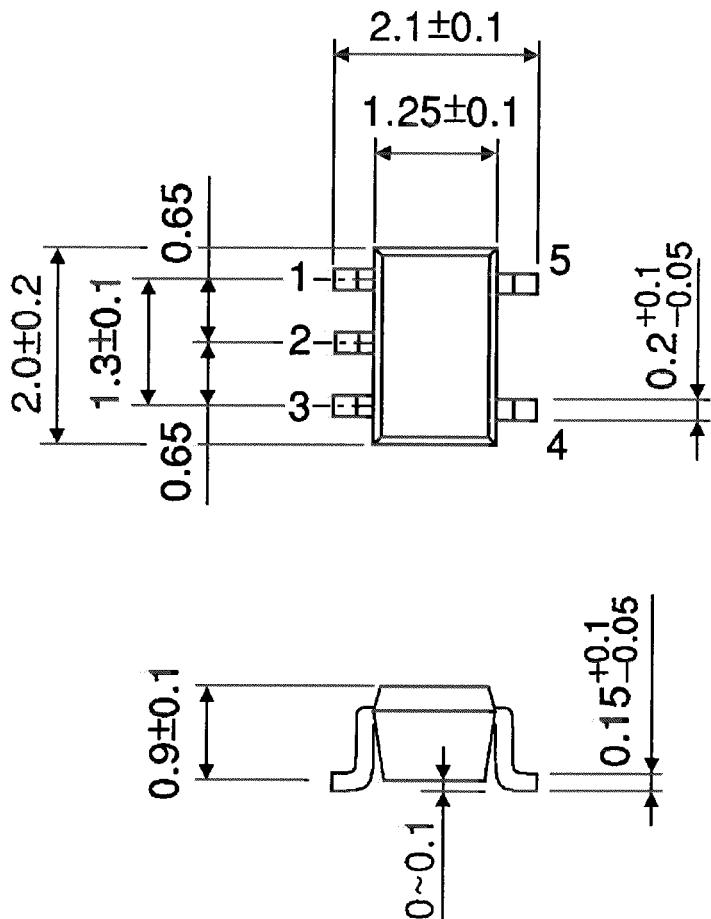


Weight: 0.014 g (typ.)

**Package Dimensions**

SSOP5-P-0.65A

Unit : mm

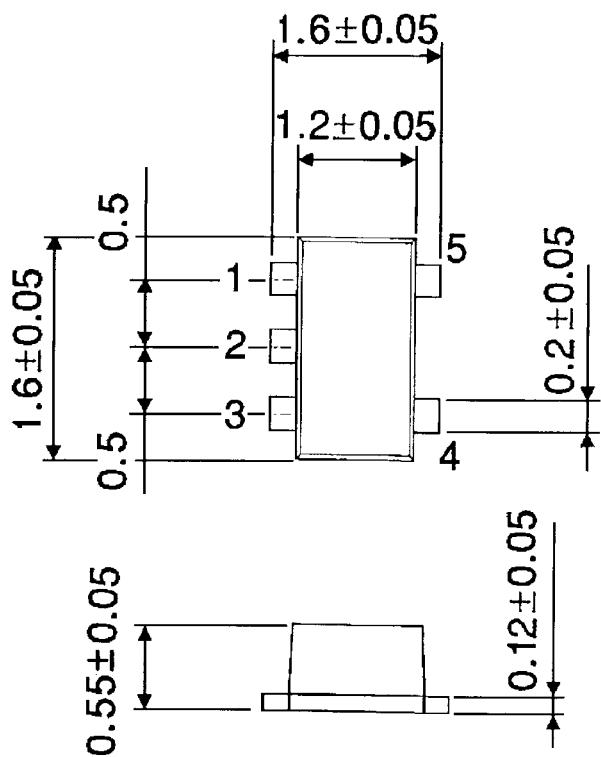


Weight: 0.006 g (typ.)

**Package Dimensions**

SON5-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

## RESTRICTIONS ON PRODUCT USE

000707EBA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.  
In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The products described in this document are subject to the foreign exchange and foreign trade laws.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.
- The information contained herein is subject to change without notice.